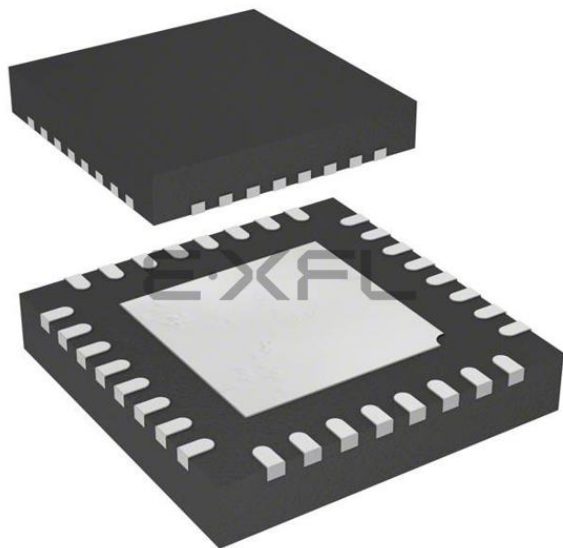




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Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M0+
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I ² C, IrDA, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, POR, PWM, WDT
Number of I/O	27
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	1.65V ~ 3.6V
Data Converters	A/D 10x12b; D/A 1x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	32-UFQFN Exposed Pad
Supplier Device Package	32-UFQFPN (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l052k8u6tr

Table 46.	16 MHz HSI16 oscillator characteristics	78
Table 47.	HSI48 oscillator characteristics	79
Table 48.	LSI oscillator characteristics	79
Table 49.	MSI oscillator characteristics	79
Table 50.	PLL characteristics	81
Table 51.	RAM and hardware registers	82
Table 52.	Flash memory and data EEPROM characteristics	82
Table 53.	Flash memory and data EEPROM endurance and retention	82
Table 54.	EMS characteristics	83
Table 55.	EMI characteristics	84
Table 56.	ESD absolute maximum ratings	85
Table 57.	Electrical sensitivities	85
Table 58.	I/O current injection susceptibility	86
Table 59.	I/O static characteristics	87
Table 60.	Output voltage characteristics	89
Table 61.	I/O AC characteristics	90
Table 62.	NRST pin characteristics	91
Table 63.	ADC characteristics	92
Table 64.	R _{AIN} max for f _{ADC} = 16 MHz	94
Table 65.	ADC accuracy	94
Table 66.	DAC characteristics	98
Table 67.	Temperature sensor calibration values	101
Table 68.	Temperature sensor characteristics	101
Table 69.	Comparator 1 characteristics	101
Table 70.	Comparator 2 characteristics	102
Table 71.	TIMx characteristics	103
Table 72.	I2C analog filter characteristics	104
Table 73.	USART/LPUART characteristics	104
Table 74.	SPI characteristics in voltage Range 1	105
Table 75.	SPI characteristics in voltage Range 2	106
Table 76.	SPI characteristics in voltage Range 3	107
Table 77.	I2S characteristics	110
Table 78.	USB startup time	112
Table 79.	USB DC electrical characteristics	112
Table 80.	USB: full speed electrical characteristics	113
Table 81.	LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package mechanical data	115
Table 82.	TFBGA64 – 64-ball, 5 x 5 mm, 0.5 mm pitch, thin profile fine pitch ball grid array package mechanical data	118
Table 83.	TFBGA64 recommended PCB design rules (0.5 mm pitch BGA)	119
Table 84.	LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package mechanical data	122
Table 85.	Standard WLCSP36 - 2.61 x 2.88 mm, 0.4 mm pitch wafer level chip scale mechanical data	124
Table 86.	Standard WLCSP36 recommended PCB design rules	125
Table 87.	Thin WLCSP36 - 2.61 x 2.88 mm, 0.4 mm pitch wafer level chip scale package mechanical data	128
Table 88.	WLCSP36 recommended PCB design rules	129
Table 89.	LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat package mechanical data	130
Table 90.	UFQFPN32 - 32-pin, 5x5 mm, 0.5 mm pitch ultra thin fine pitch quad flat package mechanical data	133
Table 91.	Thermal characteristics	135
Table 92.	STM32L052x6/8 ordering information scheme	137

List of figures

Figure 1.	STM32L052x6/8 block diagram	14
Figure 2.	Clock tree	26
Figure 3.	STM32L052x6/8 LQFP64 pinout - 10 x 10 mm	38
Figure 4.	STM32L052x6/8 TFBGA64 ballout - 5x 5 mm	39
Figure 5.	STM32L052x6/8 LQFP48 pinout - 7 x 7 mm	40
Figure 6.	STM32L052x6/8 WLCSP36 ballout	40
Figure 7.	STM32L052x6/8 LQFP32 pinout	41
Figure 8.	STM32L052x6/8 UFQFPN32 pinout	41
Figure 9.	Memory map	52
Figure 10.	Pin loading conditions	53
Figure 11.	Pin input voltage	53
Figure 12.	Power supply scheme	54
Figure 13.	Current consumption measurement scheme	54
Figure 14.	IDD vs VDD, at TA= 25/55/85/105 °C, Run mode, code running from Flash memory, Range 2, HSE, 1WS	63
Figure 15.	IDD vs VDD, at TA= 25/55/85/105 °C, Run mode, code running from Flash memory, Range 2, HSI16, 1WS	63
Figure 16.	IDD vs VDD, at TA= 25/55/ 85/105/125 °C, Low-power run mode, code running from RAM, Range 3, MSI (Range 0) at 64 KHz, 0 WS	67
Figure 17.	IDD vs VDD, at TA= 25/55/ 85/105/125 °C, Stop mode with RTC enabled and running on LSE Low drive	68
Figure 18.	IDD vs VDD, at TA= 25/55/85/105/125 °C, Stop mode with RTC disabled, all clocks OFF	68
Figure 19.	High-speed external clock source AC timing diagram	74
Figure 20.	Low-speed external clock source AC timing diagram	75
Figure 21.	HSE oscillator circuit diagram	76
Figure 22.	Typical application with a 32.768 kHz crystal	77
Figure 23.	HSI16 minimum and maximum value versus temperature	78
Figure 24.	VIH/VIL versus VDD (CMOS I/Os)	88
Figure 25.	VIH/VIL versus VDD (TTL I/Os)	88
Figure 26.	I/O AC characteristics definition	91
Figure 27.	Recommended NRST pin protection	92
Figure 28.	ADC accuracy characteristics	95
Figure 29.	Typical connection diagram using the ADC	96
Figure 30.	Power supply and reference decoupling (V_{REF+} not connected to V_{DDA})	96
Figure 31.	Power supply and reference decoupling (V_{REF+} connected to V_{DDA})	97
Figure 32.	12-bit buffered/non-buffered DAC	100
Figure 33.	SPI timing diagram - slave mode and CPHA = 0	108
Figure 34.	SPI timing diagram - slave mode and CPHA = 1 ⁽¹⁾	108
Figure 35.	SPI timing diagram - master mode ⁽¹⁾	109
Figure 36.	I ² S slave timing diagram (Philips protocol) ⁽¹⁾	111
Figure 37.	I ² S master timing diagram (Philips protocol) ⁽¹⁾	111
Figure 38.	USB timings: definition of data signal rise and fall time	112
Figure 39.	LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package outline	114
Figure 40.	LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat recommended footprint	116
Figure 41.	LQFP64 marking example (package top view)	117
Figure 42.	TFBGA64 – 64-ball, 5 x 5 mm, 0.5 mm pitch thin profile fine pitch ball grid array package outline	118

Table 3. Functionalities depending on the operating power supply range

Operating power supply range	Functionalities depending on the operating power supply range			
	DAC and ADC operation	Dynamic voltage scaling range	I/O operation	USB
$V_{DD} = 1.65$ to 1.71 V	ADC only, conversion time up to 570 ksp/s	Range 2 or range 3	Degraded speed performance	Not functional
$V_{DD} = 1.71$ to 1.8 V ⁽¹⁾	ADC only, conversion time up to 1.14 Msp/s	Range 1, range 2 or range 3	Degraded speed performance	Functional ⁽²⁾
$V_{DD} = 1.8$ to 2.0 V ⁽¹⁾	Conversion time up to 1.14 Msp/s	Range 1, range 2 or range 3	Degraded speed performance	Functional ⁽²⁾
$V_{DD} = 2.0$ to 2.4 V	Conversion time up to 1.14 Msp/s	Range 1, range 2 or range 3	Full speed operation	Functional ⁽²⁾
$V_{DD} = 2.4$ to 3.6 V	Conversion time up to 1.14 Msp/s	Range 1, range 2 or range 3	Full speed operation	Functional ⁽²⁾

1. CPU frequency changes from initial to final must respect "fcpu initial < 4*fcpu final". It must also respect 5 μ s delay between two changes. For example to switch from 4.2 MHz to 32 MHz, you can switch from 4.2 MHz to 16 MHz, wait 5 μ s, then switch from 16 MHz to 32 MHz.

2. To be USB compliant from the I/O voltage standpoint, the minimum V_{DD_USB} is 3.0 V.

Table 4. CPU frequency range depending on dynamic voltage scaling

CPU frequency range	Dynamic voltage scaling range
16 MHz to 32 MHz (1ws) 32 kHz to 16 MHz (0ws)	Range 1
8 MHz to 16 MHz (1ws) 32 kHz to 8 MHz (0ws)	Range 2
32 kHz to 4.2 MHz (0ws)	Range 3

3.3 ARM® Cortex®-M0+ core with MPU

The Cortex-M0+ processor is an entry-level 32-bit ARM Cortex processor designed for a broad range of embedded applications. It offers significant benefits to developers, including:

- a simple architecture that is easy to learn and program
- ultra-low power, energy-efficient operation
- excellent code density
- deterministic, high-performance interrupt handling
- upward compatibility with Cortex-M processor family
- platform security robustness, with integrated Memory Protection Unit (MPU).

The Cortex-M0+ processor is built on a highly area and power optimized 32-bit processor core, with a 2-stage pipeline Von Neumann architecture. The processor delivers exceptional energy efficiency through a small but powerful instruction set and extensively optimized design, providing high-end processing hardware including a single-cycle multiplier.

The Cortex-M0+ processor provides the exceptional performance expected of a modern 32-bit architecture, with a higher code density than other 8-bit and 16-bit microcontrollers.

Owing to its embedded ARM core, the STM32L052x6/8 are compatible with all ARM tools and software.

Nested vectored interrupt controller (NVIC)

The ultra-low-power STM32L052x6/8 embed a nested vectored interrupt controller able to handle up to 32 maskable interrupt channels and 4 priority levels.

The Cortex-M0+ processor closely integrates a configurable Nested Vectored Interrupt Controller (NVIC), to deliver industry-leading interrupt performance. The NVIC:

- includes a Non-Maskable Interrupt (NMI)
- provides zero jitter interrupt option
- provides four interrupt priority levels

The tight integration of the processor core and NVIC provides fast execution of Interrupt Service Routines (ISRs), dramatically reducing the interrupt latency. This is achieved through the hardware stacking of registers, and the ability to abandon and restart load-multiple and store-multiple operations. Interrupt handlers do not require any assembler wrapper code, removing any code overhead from the ISRs. Tail-chaining optimization also significantly reduces the overhead when switching from one ISR to another.

To optimize low-power designs, the NVIC integrates with the sleep modes, that include a deep sleep function that enables the entire device to enter rapidly stop or standby mode.

This hardware block provides flexible interrupt management features with minimal interrupt latency.

3.4 Reset and supply management

3.4.1 Power supply schemes

- $V_{DD} = 1.65$ to 3.6 V: external power supply for I/Os and the internal regulator. Provided externally through V_{DD} pins.
- V_{SSA} , $V_{DDA} = 1.65$ to 3.6 V: external analog power supplies for ADC, DAC, reset blocks, RCs and PLL (minimum voltage to be applied to V_{DDA} is 1.8 V when the DAC is used). V_{DDA} and V_{SSA} must be connected to V_{DD} and V_{SS} , respectively.
- $V_{DD_USB} = 1.65$ to 3.6 V: external power supply for USB transceiver, USB_DM (PA11) and USB_DP (PA12). To guarantee a correct voltage level for USB communication V_{DD_USB} must be above 3.0 V. If USB is not used this pin must be tied to V_{DD} .

3.4.2 Power supply supervisor

The devices have an integrated ZEROPOWER power-on reset (POR)/power-down reset (PDR) that can be coupled with a brownout reset (BOR) circuitry.

Two versions are available:

- The version with BOR activated at power-on operates between 1.8 V and 3.6 V.
- The other version without BOR operates between 1.65 V and 3.6 V.

After the V_{DD} threshold is reached (1.65 V or 1.8 V depending on the BOR which is active or not at power-on), the option byte loading process starts, either to confirm or modify default thresholds, or to disable the BOR permanently: in this case, the V_{DD} min value becomes 1.65 V (whatever the version, BOR active or not, at power-on).

When BOR is active at power-on, it ensures proper operation starting from 1.8 V whatever the power ramp-up phase before it reaches 1.8 V. When BOR is not active at power-up, the power ramp-up should guarantee that 1.65 V is reached on V_{DD} at least 1 ms after it exits the POR area.

Five BOR thresholds are available through option bytes, starting from 1.8 V to 3 V. To reduce the power consumption in Stop mode, it is possible to automatically switch off the internal reference voltage (V_{REFINT}) in Stop mode. The device remains in reset mode when V_{DD} is below a specified threshold, $V_{POR/PDR}$ or V_{BOR} , without the need for any external reset circuit.

Note: *The start-up time at power-on is typically 3.3 ms when BOR is active at power-up, the start-up time at power-on can be decreased down to 1 ms typically for devices with BOR inactive at power-up.*

The devices feature an embedded programmable voltage detector (PVD) that monitors the V_{DD}/V_{DDA} power supply and compares it to the V_{PVD} threshold. This PVD offers 7 different levels between 1.85 V and 3.05 V, chosen by software, with a step around 200 mV. An interrupt can be generated when V_{DD}/V_{DDA} drops below the V_{PVD} threshold and/or when V_{DD}/V_{DDA} is higher than the V_{PVD} threshold. The interrupt service routine can then generate a warning message and/or put the MCU into a safe state. The PVD is enabled by software.

To improve the accuracy of the temperature sensor measurement, each device is individually factory-calibrated by ST. The temperature sensor factory calibration data are stored by ST in the system memory area, accessible in read-only mode.

Table 7. Temperature sensor calibration values

Calibration value name	Description	Memory address
TSENSE_CAL1	TS ADC raw data acquired at temperature of 30 °C, $V_{DDA} = 3\text{ V}$	0x1FF8 007A - 0x1FF8 007B
TSENSE_CAL2	TS ADC raw data acquired at temperature of 130 °C $V_{DDA} = 3\text{ V}$	0x1FF8 007E - 0x1FF8 007F

3.12.1 Internal voltage reference (V_{REFINT})

The internal voltage reference (V_{REFINT}) provides a stable (bandgap) voltage output for the ADC and Comparators. V_{REFINT} is internally connected to the ADC_IN17 input channel. It enables accurate monitoring of the V_{DD} value (when no external voltage, V_{REF+} , is available for ADC). The precise voltage of V_{REFINT} is individually measured for each part by ST during production test and stored in the system memory area. It is accessible in read-only mode.

Table 8. Internal voltage reference measured values

Calibration value name	Description	Memory address
VREFINT_CAL	Raw data acquired at temperature of 25 °C $V_{DDA} = 3\text{ V}$	0x1FF8 0078 - 0x1FF8 0079

3.13 Digital-to-analog converter (DAC)

One 12-bit buffered DAC can be used to convert digital signal into analog voltage signal output. An optional amplifier can be used to reduce the output signal impedance.

This digital Interface supports the following features:

- One data holding register
- Left or right data alignment in 12-bit mode
- Synchronized update capability
- Noise-wave generation
- Triangular-wave generation
- DMA capability (including the underrun interrupt)
- External triggers for conversion
- Input reference voltage V_{REF+}

Four DAC trigger inputs are used in the STM32L052x6/8. The DAC channel is triggered through the timer update outputs that are also connected to different DMA channels.

3.14 Ultra-low-power comparators and reference voltage

The STM32L052x6/8 embed two comparators sharing the same current bias and reference voltage. The reference voltage can be internal or external (coming from an I/O).

- One comparator with ultra low consumption
- One comparator with rail-to-rail inputs, fast or slow mode.
- The threshold can be one of the following:
 - DAC output
 - External I/O pins
 - Internal reference voltage (V_{REFINT})
 - submultiple of Internal reference voltage (1/4, 1/2, 3/4) for the rail to rail comparator.

Both comparators can wake up the devices from Stop mode, and be combined into a window comparator.

The internal reference voltage is available externally via a low-power / low-current output buffer (driving current capability of 1 μ A typical).

3.15 System configuration controller

The system configuration controller provides the capability to remap some alternate functions on different I/O ports.

The highly flexible routing interface allows the application firmware to control the routing of different I/Os to the TIM2, TIM21, TIM22 and LPTIM timer input captures. It also controls the routing of internal analog signals to the USB internal oscillator, ADC, COMP1 and COMP2 and the internal reference voltage V_{REFINT} .

3.16 Touch sensing controller (TSC)

The STM32L052x6/8 provide a simple solution for adding capacitive sensing functionality to any application. These devices offer up to 24 capacitive sensing channels distributed over 8 analog I/O groups.

Capacitive sensing technology is able to detect the presence of a finger near a sensor which is protected from direct touch by a dielectric (such as glass, plastic). The capacitive variation introduced by the finger (or any conductive object) is measured using a proven implementation based on a surface charge transfer acquisition principle. It consists of charging the sensor capacitance and then transferring a part of the accumulated charges into a sampling capacitor until the voltage across this capacitor has reached a specific threshold. To limit the CPU bandwidth usage, this acquisition is directly managed by the hardware touch sensing controller and only requires few external components to operate.

The touch sensing controller is fully supported by the STMTouch touch sensing firmware library, which is free to use and allows touch sensing functionality to be implemented reliably in the end application.

Each I2C interface can be served by the DMA controller.

Refer to [Table 12](#) for an overview of I2C interface features.

Table 12. STM32L052x6/8 I²C implementation

I2C features ⁽¹⁾	I2C1	I2C2
7-bit addressing mode	X	X
10-bit addressing mode	X	X
Standard mode (up to 100 kbit/s)	X	X
Fast mode (up to 400 kbit/s)	X	X
Fast Mode Plus with 20 mA output drive I/Os (up to 1 Mbit/s)	X	X ⁽²⁾
Independent clock	X	-
SMBus	X	-
Wakeup from STOP	X	-

1. X = supported.

2. See [Table 1](#) for the list of I/Os that feature Fast Mode Plus capability

3.18.2 Universal synchronous/asynchronous receiver transmitter (USART)

The two USART interfaces (USART1, USART2) are able to communicate at speeds of up to 4 Mbit/s.

They provide hardware management of the CTS, RTS and RS485 driver enable (DE) signals, multiprocessor communication mode, master synchronous communication and single-wire half-duplex communication mode. They also support SmartCard communication (ISO 7816), IrDA SIR ENDEC, LIN Master/Slave capability, auto baud rate feature and has a clock domain independent from the CPU clock, allowing to wake up the MCU from Stop mode using baudrates up to 42 Kbaud.

All USART interfaces can be served by the DMA controller.

[Table 13](#) for the supported modes and features of USART interfaces.

Table 13. USART implementation

USART modes/features ⁽¹⁾	USART1 and USART2
Hardware flow control for modem	X
Continuous communication using DMA	X
Multiprocessor communication	X
Synchronous mode ⁽²⁾	X
Smartcard mode	X
Single-wire half-duplex communication	X
IrDA SIR ENDEC block	X
LIN mode	X
Dual clock domain and wakeup from Stop mode	X
Receiver timeout interrupt	X

Table 15. Legend/abbreviations used in the pinout table

Name		Abbreviation	Definition
Pin name		Unless otherwise specified in brackets below the pin name, the pin function during and after reset is the same as the actual pin name	
Pin type		S	Supply pin
		I	Input only pin
		I/O	Input / output pin
I/O structure		FT	5 V tolerant I/O
		FTf	5 V tolerant I/O, FM+ capable
		TC	Standard 3.3V I/O
		B	Dedicated BOOT0 pin
		RST	Bidirectional reset pin with embedded weak pull-up resistor
Notes		Unless otherwise specified by a note, all I/Os are set as floating inputs during and after reset.	
Pin functions	Alternate functions	Functions selected through GPIOx_AFR registers	
	Additional functions	Functions directly selected/enabled through peripheral registers	

Table 16. STM32L052x6/8 pin definitions

Pin Number						Pin name (function after reset)	Pin type	I/O structure	Notes	Alternate functions	Additional functions
LQFP32	UFQFN32	WLCSP36 ⁽¹⁾	LQFP48	LQFP64	TFBGA64						
-	-	-	1	1	B2	VDD	S	-	-	-	-
-	-	-	2	2	A2	PC13	I/O	FT	-	-	RTC_TAMP1/ RTC_TS/RTC _OUT/WKUP2
2	2	A6	3	3	A1	PC14- OSC32_IN (PC14)	I/O	FT	-	-	OSC32_IN
3	3	B6	4	4	B1	PC15- OSC32_OUT (PC15)	I/O	TC	-	-	OSC32_OUT

Figure 14. I_{DD} vs V_{DD} , at $T_A = 25/55/85/105\text{ }^{\circ}\text{C}$, Run mode, code running from Flash memory, Range 2, HSE, 1WS

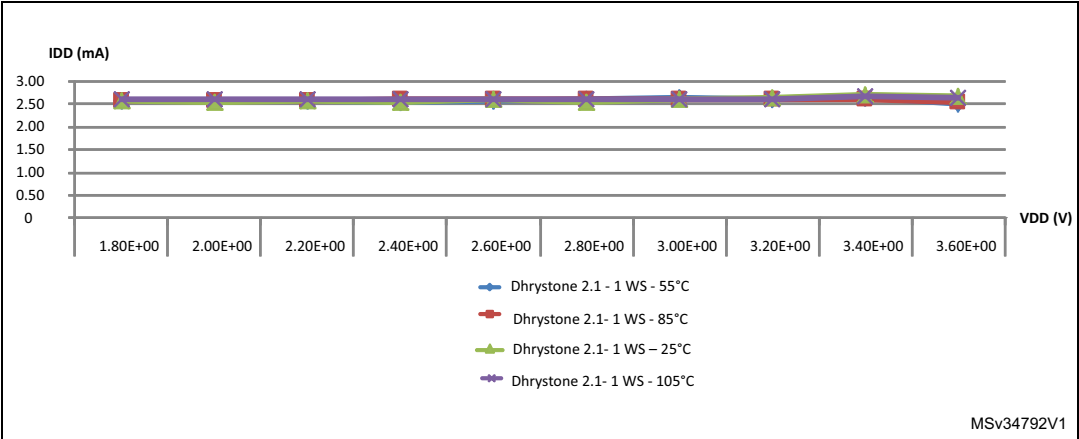


Figure 15. I_{DD} vs V_{DD} , at $T_A = 25/55/85/105\text{ }^{\circ}\text{C}$, Run mode, code running from Flash memory, Range 2, HSI16, 1WS

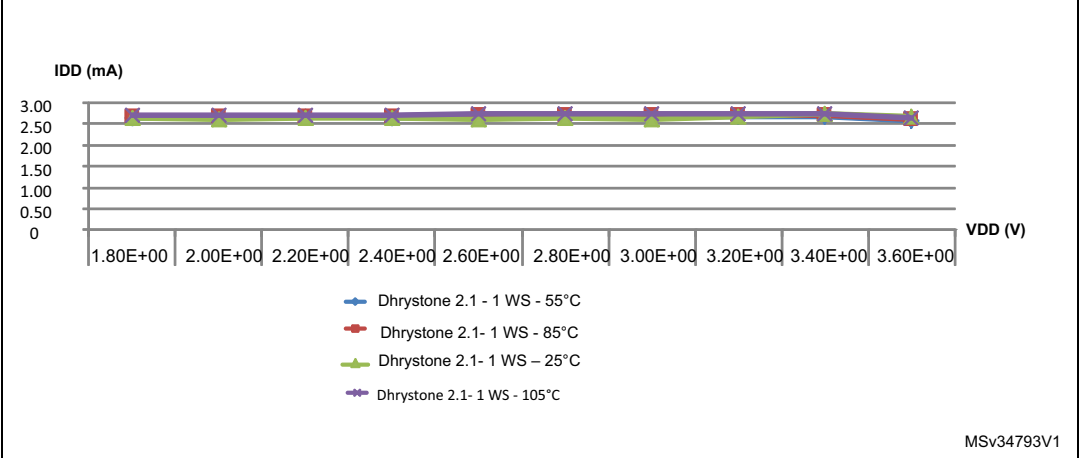


Table 41. Low-power mode wakeup timings (continued)

Symbol	Parameter	Conditions	Typ	Max	Unit
t_{WUSTOP}	Wakeup from Stop mode, regulator in Run mode	$f_{HCLK} = f_{MSI} = 4.2 \text{ MHz}$	5.0	8	μs
		$f_{HCLK} = f_{HSI} = 16 \text{ MHz}$	4.9	7	
		$f_{HCLK} = f_{HSI}/4 = 4 \text{ MHz}$	8.0	11	
	Wakeup from Stop mode, regulator in low-power mode	$f_{HCLK} = f_{MSI} = 4.2 \text{ MHz}$ Voltage range 1	5.0	8	
		$f_{HCLK} = f_{MSI} = 4.2 \text{ MHz}$ Voltage range 2	5.0	8	
		$f_{HCLK} = f_{MSI} = 4.2 \text{ MHz}$ Voltage range 3	5.0	8	
		$f_{HCLK} = f_{MSI} = 2.1 \text{ MHz}$	7.3	13	
		$f_{HCLK} = f_{MSI} = 1.05 \text{ MHz}$	13	23	
		$f_{HCLK} = f_{MSI} = 524 \text{ kHz}$	28	38	
		$f_{HCLK} = f_{MSI} = 262 \text{ kHz}$	51	65	
		$f_{HCLK} = f_{MSI} = 131 \text{ kHz}$	100	120	
		$f_{HCLK} = f_{MSI} = 65 \text{ kHz}$	190	260	
		$f_{HCLK} = f_{HSI} = 16 \text{ MHz}$	4.9	7	
		$f_{HCLK} = f_{HSI}/4 = 4 \text{ MHz}$	8.0	11	
	Wakeup from Stop mode, regulator in low-power mode, code running from RAM	$f_{HCLK} = f_{HSI} = 16 \text{ MHz}$	4.9	7	
		$f_{HCLK} = f_{HSI}/4 = 4 \text{ MHz}$	7.9	10	
		$f_{HCLK} = f_{MSI} = 4.2 \text{ MHz}$	4.7	8	
$t_{WUSTDBY}$	Wakeup from Standby mode, FWU bit = 1	$f_{HCLK} = f_{MSI} = 2.1 \text{ MHz}$	65	130	μs
	Wakeup from Standby mode, FWU bit = 0	$f_{HCLK} = f_{MSI} = 2.1 \text{ MHz}$	2.2	3	ms

6.3.6 External clock source characteristics

High-speed external user clock generated from an external source

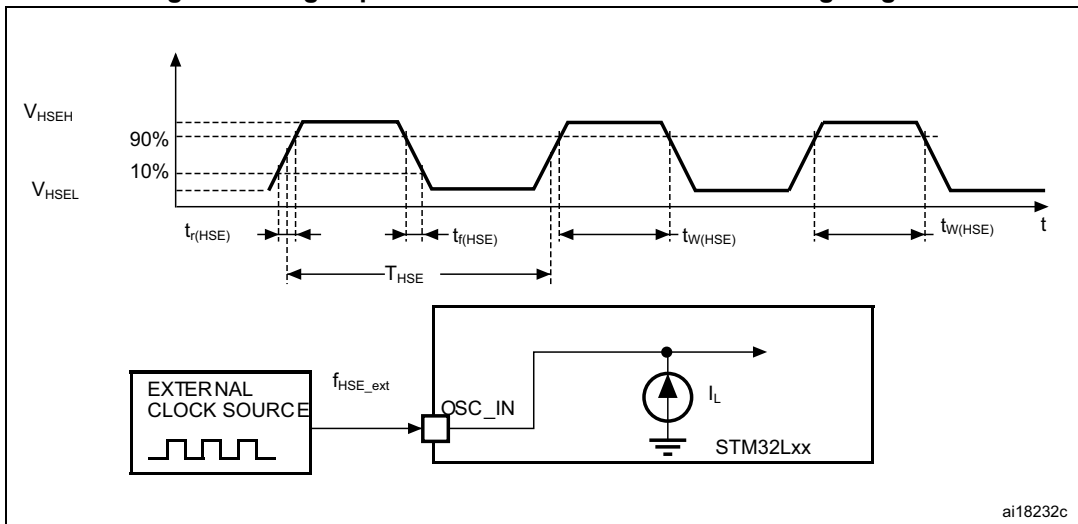
In bypass mode the HSE oscillator is switched off and the input pin is a standard GPIO. The external clock signal has to respect the I/O characteristics in [Section 6.3.12](#). However, the recommended clock input waveform is shown in [Figure 19](#).

Table 42. High-speed external user clock characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HSE_ext}	User external clock source frequency	CSS is ON or PLL is used	1	8	32	MHz
		CSS is OFF, PLL not used	0	8	32	MHz
V_{HSEH}	OSC_IN input pin high level voltage	-	$0.7V_{DD}$	-	V_{DD}	V
V_{HSEL}	OSC_IN input pin low level voltage		V_{SS}	-	$0.3V_{DD}$	
$t_{w(HSE)}$ $t_{w(HSE)}$	OSC_IN high or low time		12	-	-	ns
$t_{r(HSE)}$ $t_{f(HSE)}$	OSC_IN rise or fall time		-	-	20	
$C_{in(HSE)}$	OSC_IN input capacitance		-	2.6	-	pF
$DuCy_{(HSE)}$	Duty cycle		45	-	55	%
I_L	OSC_IN Input leakage current	$V_{SS} \leq V_{IN} \leq V_{DD}$	-	-	± 1	μA

1. Guaranteed by design.

Figure 19. High-speed external clock source AC timing diagram



6.3.16 DAC electrical characteristics

Data guaranteed by design, not tested in production, unless otherwise specified.

Table 66. DAC characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{DDA}	Analog supply voltage	-	1.8	-	3.6	V
V_{REF+}	Reference supply voltage	V_{REF+} must always be below V_{DDA}	1.8	-	3.6	V
V_{REF-}	Lower reference voltage	-	V_{SSA}			V
$I_{DDVREF+}^{(1)}$	Current consumption on V_{REF+} supply $V_{REF+} = 3.3$ V	No load, middle code (0x800)	-	130	220	μ A
		No load, worst code (0x000)	-	220	350	
$I_{DDA}^{(2)}$	Current consumption on V_{DDA} supply, $V_{DDA} = 3.3$ V	No load, middle code (0x800)	-	210	320	μ A
		No load, worst code (0xF1C)	-	320	520	
$R_L^{(3)}$	Resistive load	DAC output ON R_L connected to V_{SSA}	5	-	-	k Ω
		R_L connected to V_{DDA}	25	-	-	
$C_L^{(3)}$	Capacitive load	DAC output buffer ON	-	-	50	pF
R_O	Output impedance	DAC output buffer OFF	12	16	20	k Ω
V_{DAC_OUT}	Voltage on DAC_OUT output	DAC output buffer ON	0.2	-	$V_{DDA} - 0.2$	V
		DAC output buffer OFF	0.5	-	$V_{REF+} - 1\text{LSB}$	mV

Table 70. Comparator 2 characteristics

Symbol	Parameter	Conditions	Min	Typ	Max ⁽¹⁾	Unit
V_{DDA}	Analog supply voltage	-	1.65	-	3.6	V
V_{IN}	Comparator 2 input voltage range	-	0	-	V_{DDA}	V
t_{START}	Comparator startup time	Fast mode	-	15	20	μs
		Slow mode	-	20	25	
$t_{d\ slow}$	Propagation delay ⁽²⁾ in slow mode	$1.65\ V \leq V_{DDA} \leq 2.7\ V$	-	1.8	3.5	
		$2.7\ V \leq V_{DDA} \leq 3.6\ V$	-	2.5	6	
$t_{d\ fast}$	Propagation delay ⁽²⁾ in fast mode	$1.65\ V \leq V_{DDA} \leq 2.7\ V$	-	0.8	2	
		$2.7\ V \leq V_{DDA} \leq 3.6\ V$	-	1.2	4	
V_{offset}	Comparator offset error		-	± 4	± 20	mV
$dThreshold/dt$	Threshold voltage temperature coefficient	$V_{DDA} = 3.3\ V$, $T_A = 0\ \text{to}\ 50\ ^\circ\text{C}$, $V_- = V_{REFINT}$, $3/4\ V_{REFINT}$, $1/2\ V_{REFINT}$, $1/4\ V_{REFINT}$	-	15	30	ppm/ $^\circ\text{C}$
I_{COMP2}	Current consumption ⁽³⁾	Fast mode	-	3.5	5	μA
		Slow mode	-	0.5	2	

1. Guaranteed by characterization results.

2. The delay is characterized for 100 mV input step with 10 mV overdrive on the inverting input, the non-inverting input set to the reference.

3. Comparator consumption only. Internal reference voltage (required for comparator operation) is not included.

SPI characteristics

Unless otherwise specified, the parameters given in the following tables are derived from tests performed under ambient temperature, f_{PCLKx} frequency and V_{DD} supply voltage conditions summarized in [Table 25](#).

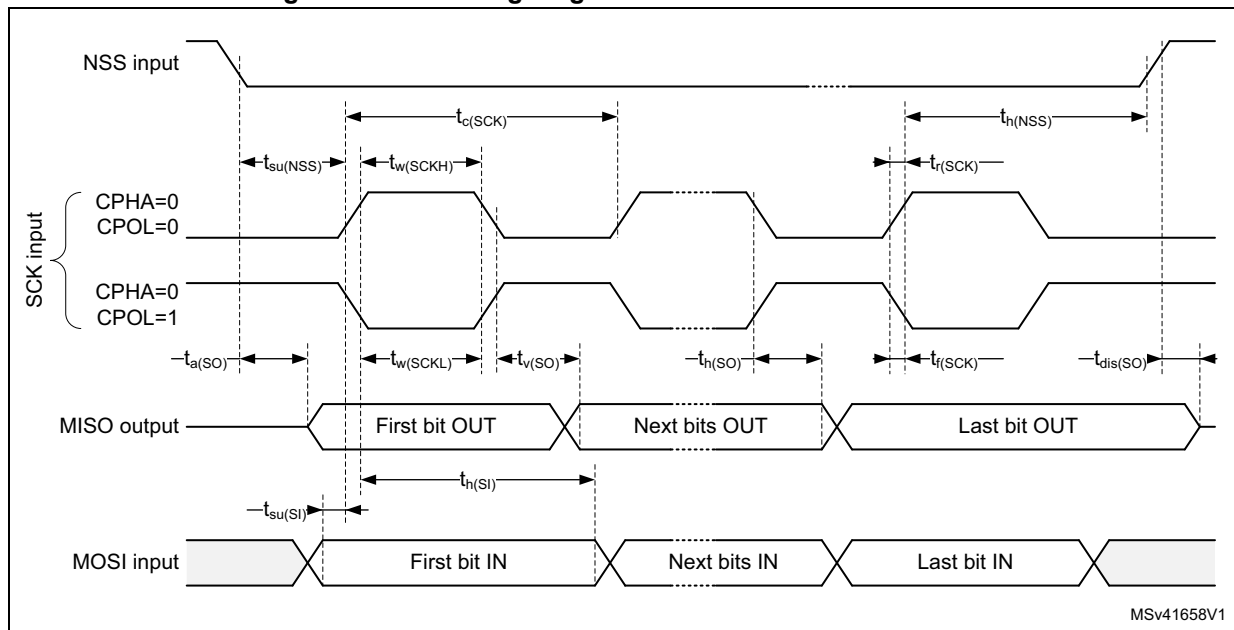
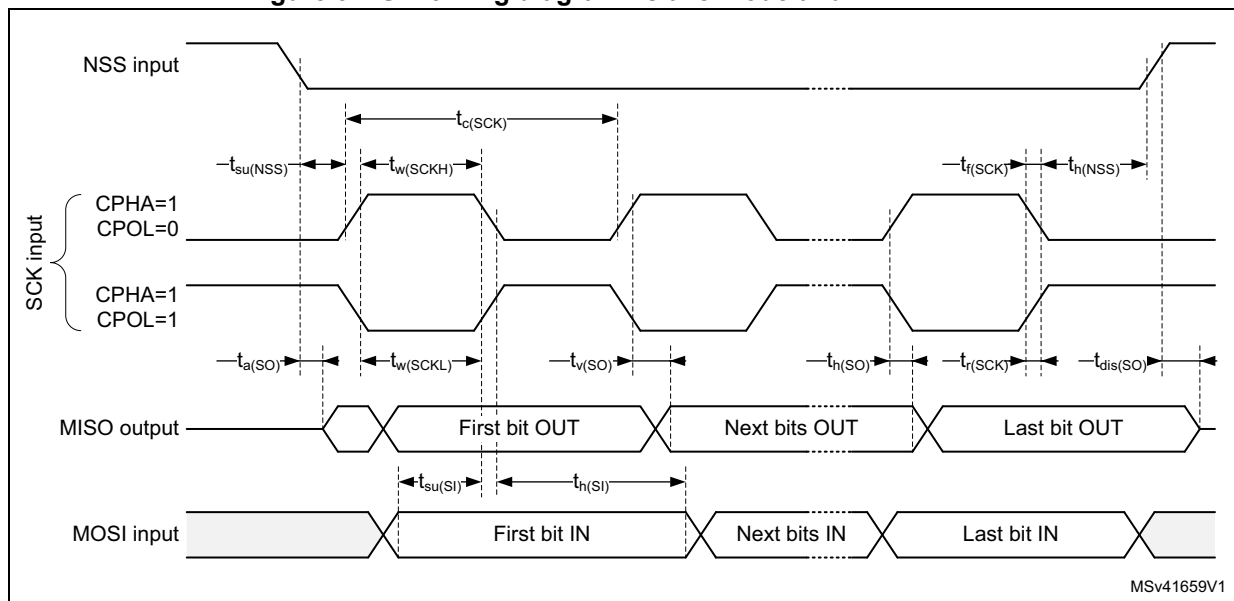
Refer to [Section 6.3.12: I/O current injection characteristics](#) for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO).

Table 74. SPI characteristics in voltage Range 1 ⁽¹⁾

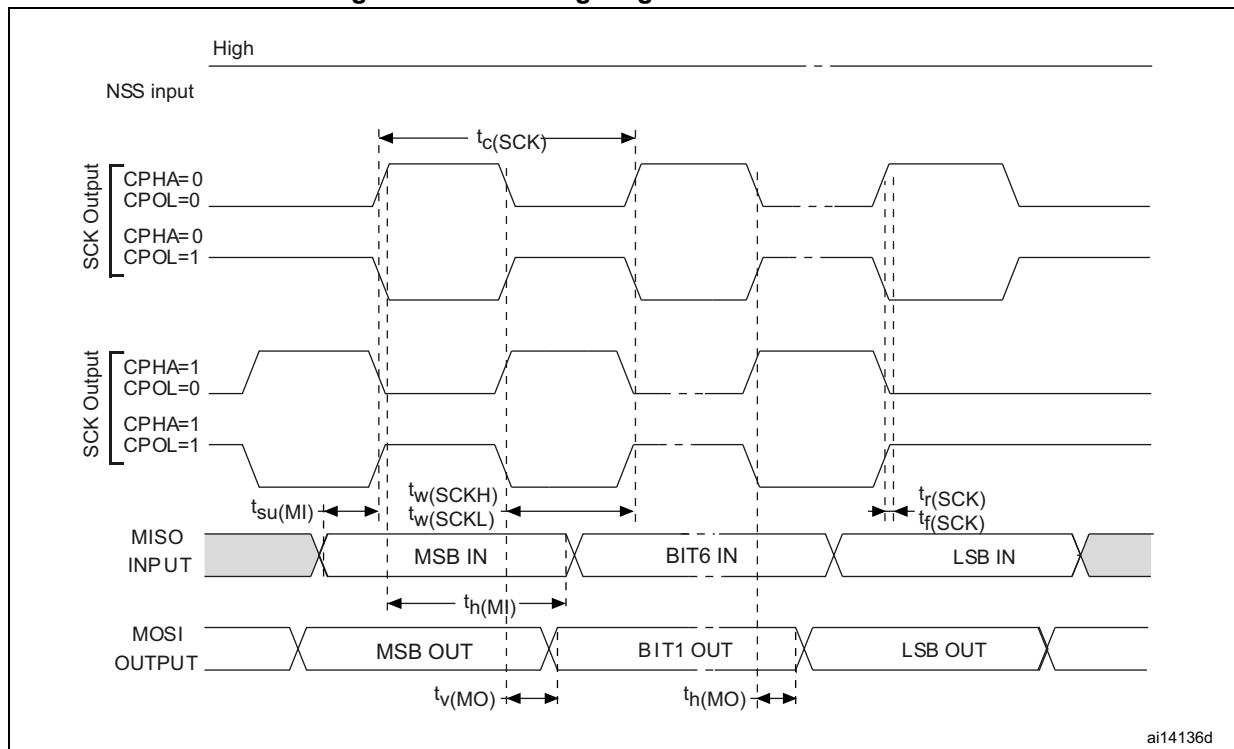
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{SCK} $1/t_{c(SCK)}$	SPI clock frequency	Master mode	-	-	16	MHz
		Slave mode receiver			16	
		Slave mode Transmitter $1.71 < V_{DD} < 3.6V$	-	-	$12^{(2)}$	
		Slave mode Transmitter $2.7 < V_{DD} < 3.6V$	-	-	$16^{(2)}$	
$Duty_{(SCK)}$	Duty cycle of SPI clock frequency	Slave mode	30	50	70	%
$t_{su(NSS)}$	NSS setup time	Slave mode, SPI presc = 2	$4 \cdot T_{pclk}$	-	-	ns
$t_{h(NSS)}$	NSS hold time	Slave mode, SPI presc = 2	$2 \cdot T_{pclk}$	-	-	
$t_{w(SCKH)}$ $t_{w(SCKL)}$	SCK high and low time	Master mode	$T_{pclk} - 2$	T_{pclk}	$T_{pclk} + 2$	
$t_{su(MI)}$	Data input setup time	Master mode	0	-	-	
$t_{su(SI)}$		Slave mode	3	-	-	
$t_{h(MI)}$	Data input hold time	Master mode	7	-	-	
$t_{h(SI)}$		Slave mode	3.5	-	-	
$t_{a(SO)}$	Data output access time	Slave mode	15	-	36	
$t_{dis(SO)}$	Data output disable time	Slave mode	10	-	30	
$t_{v(SO)}$	Data output valid time	Slave mode $1.65 V < V_{DD} < 3.6 V$	-	18	41	
		Slave mode $2.7 V < V_{DD} < 3.6 V$	-	18	25	
		Master mode	-	4	7	
$t_{h(SO)}$	Data output hold time	Slave mode	10	-	-	
$t_{h(MO)}$		Master mode	0	-	-	

1. Guaranteed by characterization results.
2. The maximum SPI clock frequency in slave transmitter mode is determined by the sum of $t_{v(SO)}$ and $t_{su(MI)}$ which has to fit into SCK low or high phase preceding the SCK sampling edge. This value can be achieved when the SPI communicates with a master having $t_{su(MI)} = 0$ while $Duty_{(SCK)} = 50\%$.

Figure 33. SPI timing diagram - slave mode and CPHA = 0

Figure 34. SPI timing diagram - slave mode and CPHA = 1⁽¹⁾

1. Measurement points are done at CMOS levels: 0.3V_{DD} and 0.7V_{DD}.

Figure 35. SPI timing diagram - master mode⁽¹⁾

1. Measurement points are done at CMOS levels: $0.3V_{DD}$ and $0.7V_{DD}$.

Table 82. TFBGA64 – 64-ball, 5 x 5 mm, 0.5 mm pitch, thin profile fine pitch ball grid array package mechanical data (continued)

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
ddd	-	-	0.080	-	-	0.0031
eee	-	-	0.150	-	-	0.0059
fff	-	-	0.050	-	-	0.0020

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 43. TFBGA64 – 64-ball, 5 x 5 mm, 0.5 mm pitch, thin profile fine pitch ball grid array recommended footprint

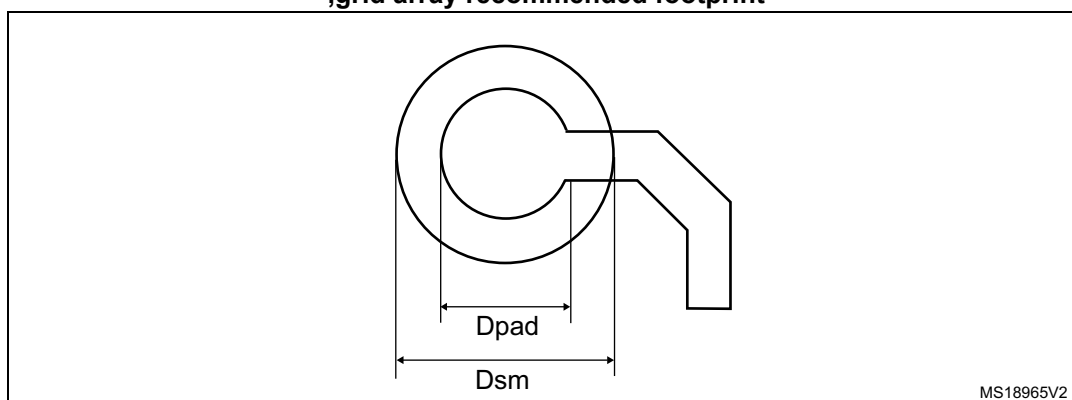


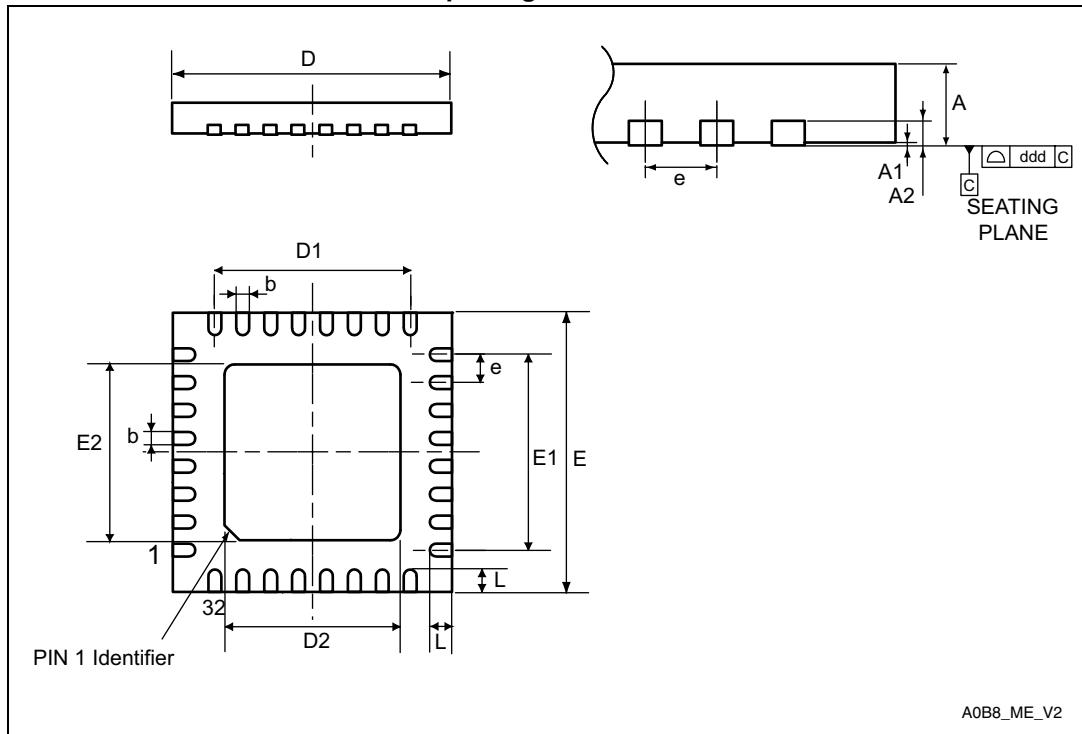
Table 83. TFBGA64 recommended PCB design rules (0.5 mm pitch BGA)

Dimension	Recommended values
Pitch	0.5
Dpad	0.27 mm
Dsm	0.35 mm typ. (depends on the soldermask registration tolerance)
Solder paste	0.27 mm aperture diameter.

Note: *Non solder mask defined (NSMD) pads are recommended.
4 to 6 mils solder paste screen printing process.*

7.7 UFQFPN32 package information

Figure 56. UFQFPN32 - 32-pin, 5x5 mm, 0.5 mm pitch ultra thin fine pitch quad flat package outline



1. Drawing is not to scale.

7.8 Thermal characteristics

The maximum chip-junction temperature, $T_J \text{ max}$, in degrees Celsius, may be calculated using the following equation:

$$T_J \text{ max} = T_A \text{ max} + (P_D \text{ max} \times \Theta_{JA})$$

Where:

- $T_A \text{ max}$ is the maximum ambient temperature in °C,
- Θ_{JA} is the package junction-to-ambient thermal resistance, in °C/W,
- $P_D \text{ max}$ is the sum of $P_{INT} \text{ max}$ and $P_{I/O} \text{ max}$ ($P_D \text{ max} = P_{INT} \text{ max} + P_{I/O} \text{ max}$),
- $P_{INT} \text{ max}$ is the product of I_{DD} and V_{DD} , expressed in Watts. This is the maximum chip internal power.

$P_{I/O} \text{ max}$ represents the maximum power dissipation on output pins where:

$$P_{I/O} \text{ max} = \Sigma (V_{OL} \times I_{OL}) + \Sigma (V_{DD} - V_{OH}) \times I_{OH},$$

taking into account the actual V_{OL} / I_{OL} and V_{OH} / I_{OH} of the I/Os at low and high level in the application.

Table 91. Thermal characteristics

Symbol	Parameter	Value	Unit
Θ_{JA}	Thermal resistance junction-ambient TFBGA64 - 5 x 5 mm / 0.5 mm pitch	61	°C/W
	Thermal resistance junction-ambient LQFP64 - 10 x 10 mm / 0.5 mm pitch	45	
	Thermal resistance junction-ambient Standard WLCSP36 - 0.4 mm pitch	63	
	Thermal resistance junction-ambient Thin WLCSP36 - 0.4 mm pitch	59	
	Thermal resistance junction-ambient LQFP48 - 7 x 7 mm / 0.5 mm pitch	55	
	Thermal resistance junction-ambient LQFP32 - 7 x 7 mm / 0.8 mm pitch	57	
	Thermal resistance junction-ambient UFQFPN32 - 5 x 5 mm / 0.5 mm pitch	38	